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1. (Fourth Amended)

A method of manufacturing a thin film chip resistor with a moisture barrier comprising:

~~EFT~~ depositing a non-tantalum metal film resistive layer directly overlaying and attaching to a thin film chip resistor substrate;

~~Sub~~ attaching a chip resistor termination on each end of the metal film resistive layer; and

~~FI~~ depositing the moisture barrier comprising a layer of tantalum pentoxide film directly overlaying and attaching to the metal film resistive layer to reduce failures due to electrolytic corrosion under powered moisture conditions.

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15. (Thrice Amended)

A method of manufacturing a thin film chip resistor with a moisture barrier comprising:

~~EFT~~ depositing a non-tantalum metal film resistive layer directly overlaying and attaching to a substrate;

~~Sub~~ attaching a chip resistor termination on each end of the metal film resistive layer;

~~FI~~ depositing a passivation layer directly overlaying and attaching to the metal film layer; and

depositing the moisture barrier comprising a layer of tantalum pentoxide film directly overlaying and attaching to the passivation layer for reducing failures due to electrolytic corrosion under powered moisture conditions.

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